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# Electric field induced instability in ultra-thin films

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# Patterns at nano/micro-scale

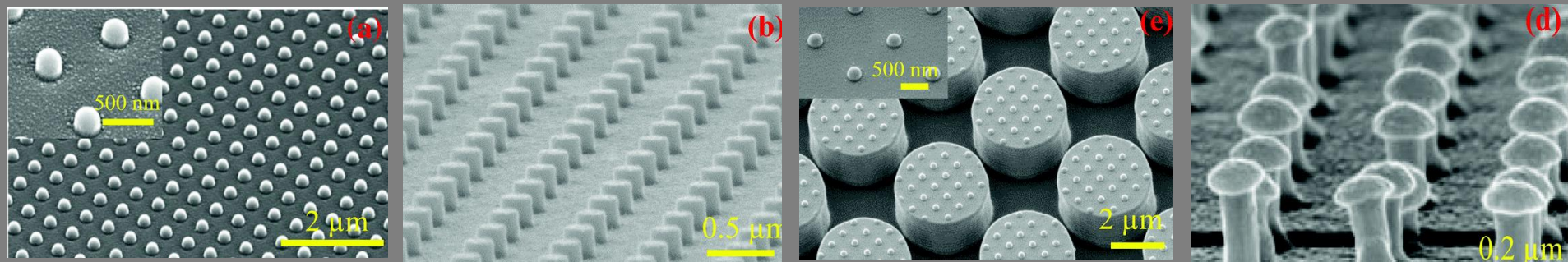
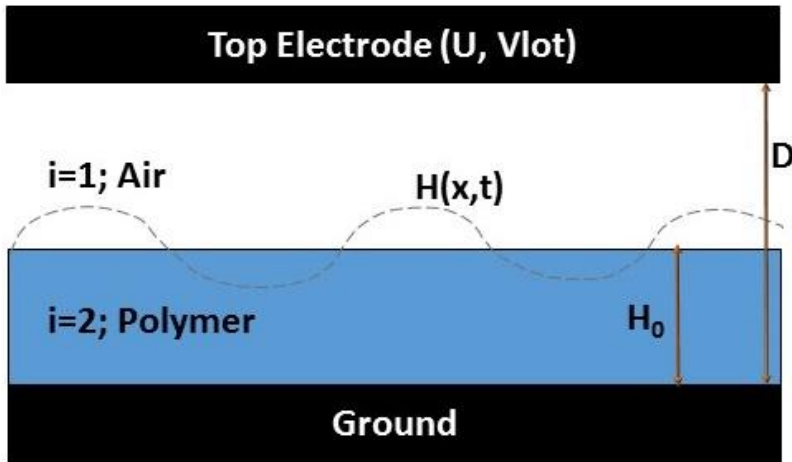


Image source: RSC, Nanotoday : DOI: 10.1039/C4NR04069D

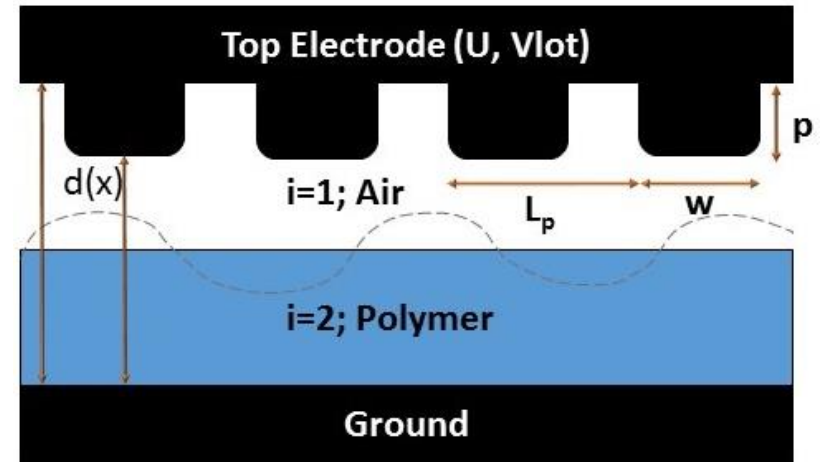
Microfluidic devices, semi-conductor devices, emulsions and coatings are just to name a few applications<sup>6</sup>

# Schematic



(a)

**Top electrode – Flat plate**  
**Homogeneous field**



(b)

**Top electrode – Patterned mask**  
**Heterogeneous field**

- Period limit ( $L_p$ ), protrude width ( $w$ ), protrude height ( $p$ ), electrode spacing ( $D$ ), lateral electrode distance ( $d$ ), and initial film thickness ( $H_0$ ) are shown in the schematic.
- Interface is perturbed either because of its own thermal fluctuations or externally. <sup>8,9,10</sup>

# Assumptions and Equations

- **2D** model is developed
- System is **isothermal**
- The polymer and air are **Newtonian** fluids
- Polymer fluid is considered to be **perfect dielectric**
- All material properties are **constant**.
- The incompressible **Navier–Stokes** equations and continuity are introduced to describe the flow.
- Inertial terms are neglected.

$$\rho_i \left[ \frac{\partial \vec{u}_i}{\partial t} + (\vec{u}_i \cdot \nabla) \vec{u}_i \right] = -\nabla p_i + \nabla \cdot \left[ \mu_i (\nabla \vec{u}_i + (\nabla \vec{u}_i)^T) \right] + \vec{f}_i$$

$$\nabla \cdot (\vec{u}_i) = 0$$

# Assumptions and Equations

- Electrical force is included as a **body force** term.
- Force acting on the interphase is given by,

$$F = -\frac{1}{2} \epsilon_0 \nabla \epsilon E \cdot E$$

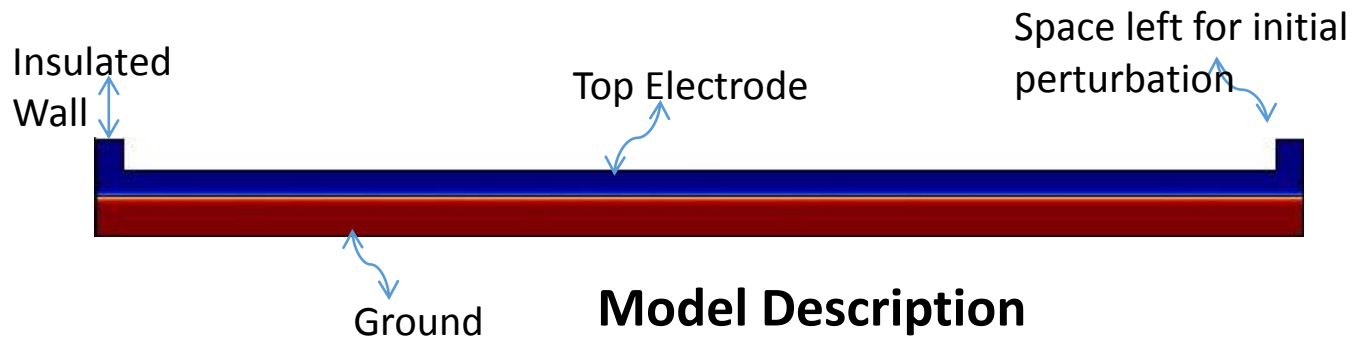
- This force can in-turn be given in a pressure force form using stress boundary condition as<sup>1,7,8</sup>,

$$P_{el} = -0.5 \epsilon_0 \epsilon (\epsilon - 1) E^2$$

- This pressure is applied as a body force term in computational model using **delta function**.
- Electrostatics module solves the **Laplace** equation,

$$\nabla \epsilon \nabla V = 0$$

# Flat electrode system

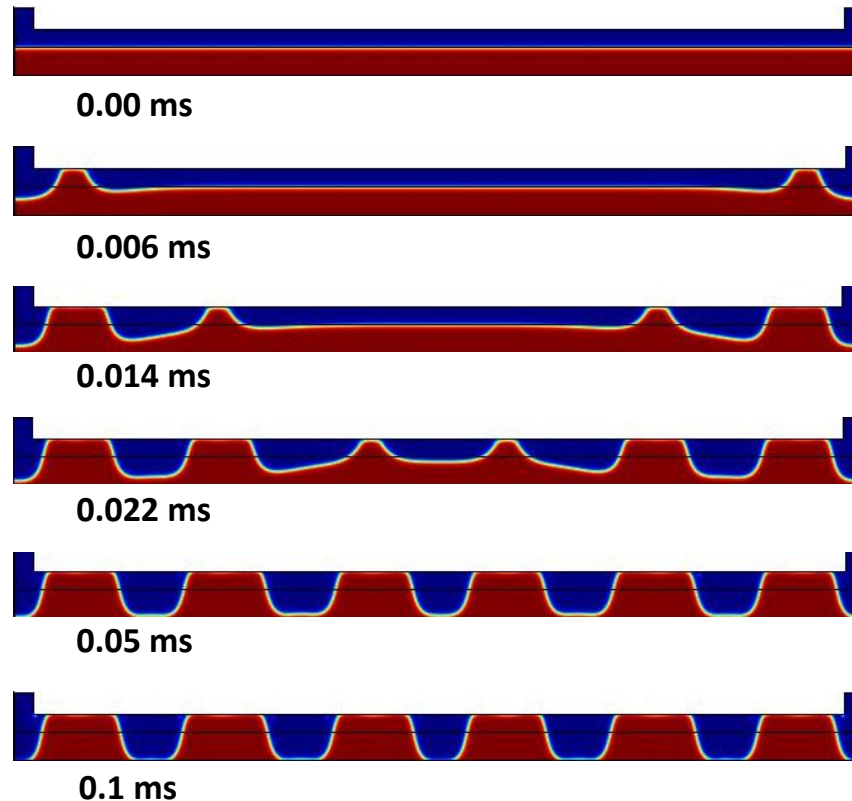


$$\lambda_c = 2\pi \sqrt{\frac{2\sigma U}{\epsilon_0 \epsilon_p (\epsilon_p - 1)}} E_p^{-3/2} \quad E_p = \frac{U}{\epsilon_p d - (\epsilon_p - 1)h}$$

## Parameters

U = 30 Volt  
 $\sigma = 0.03$  N/m  
 $\epsilon_p = 10$   
d = 250 nm  
h = 150 nm

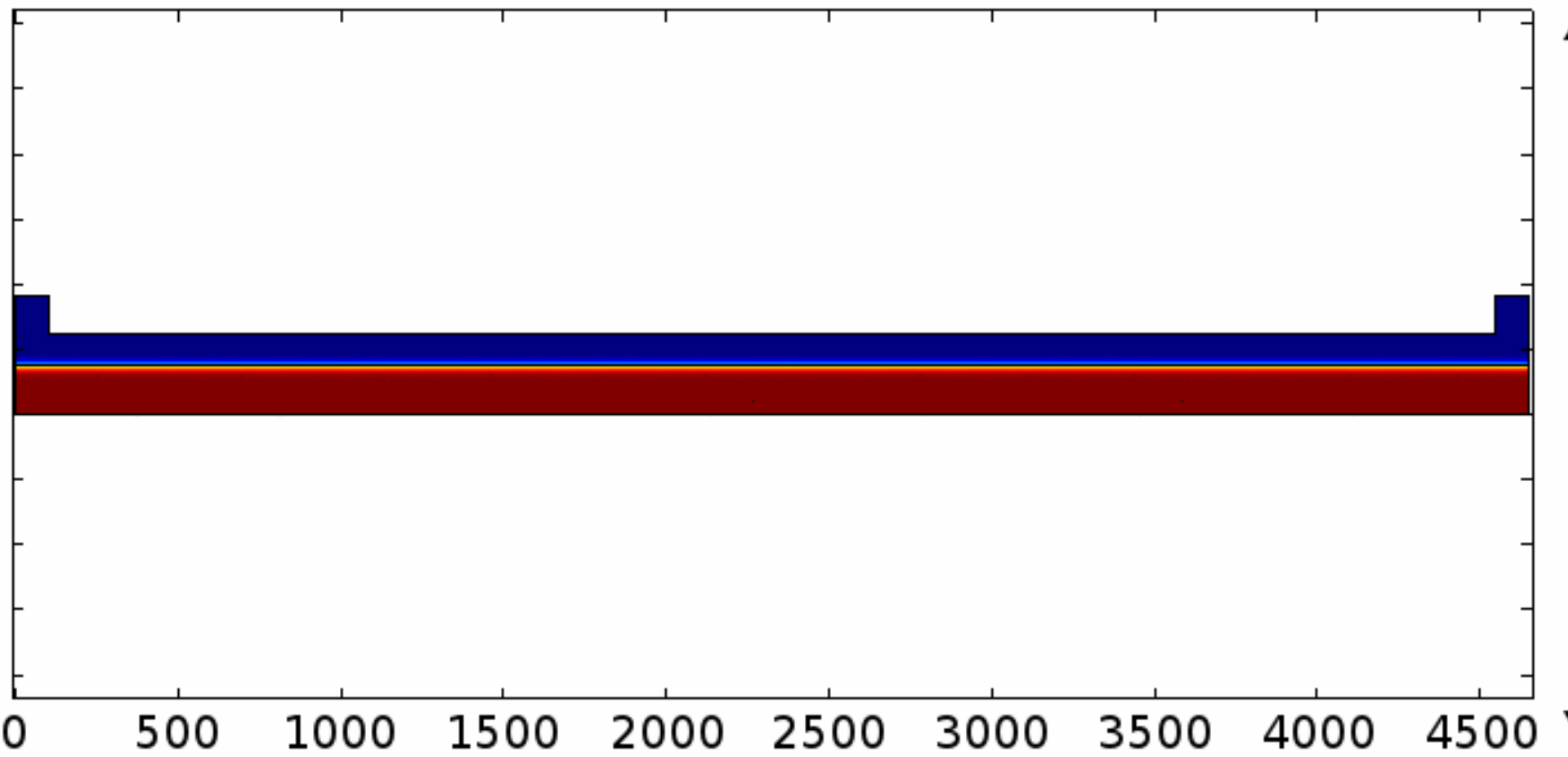
# Validation



Fastest growing wavelength=780 nm

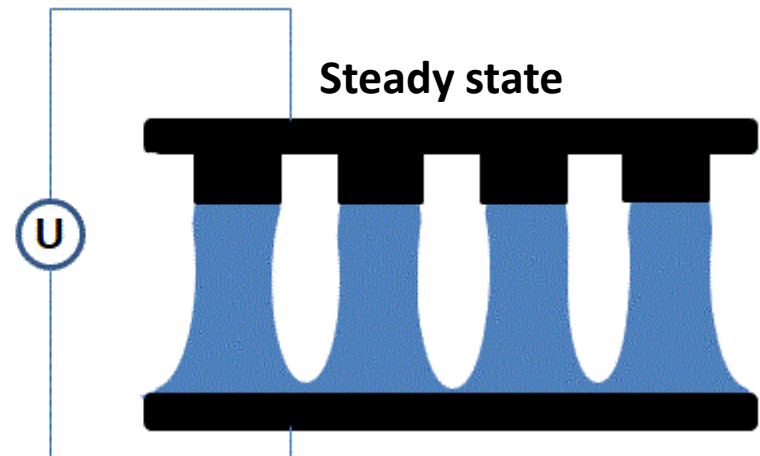
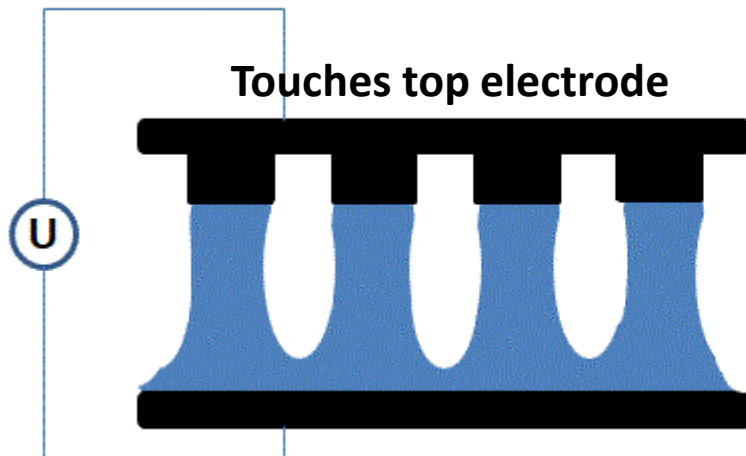
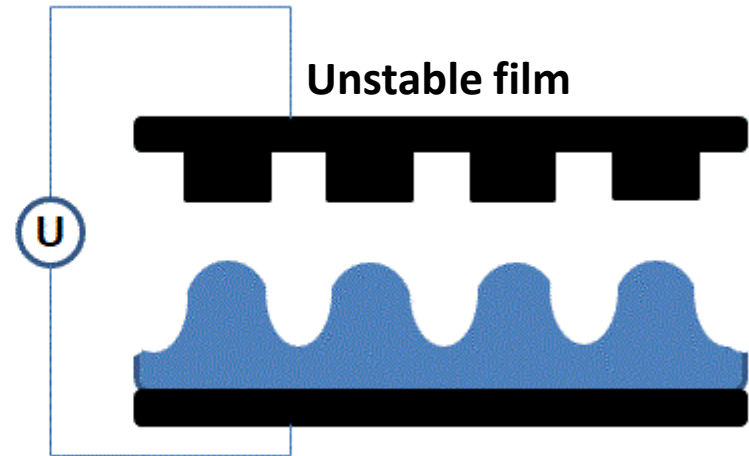
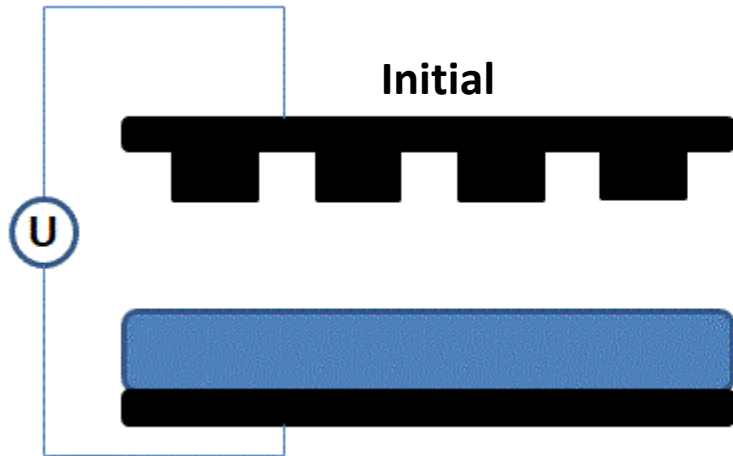
Fastest growing wavelength in linear stability analysis<sup>3</sup> =740 nm

Time=0 s Surface: Volume fraction of fluid 2 (1)

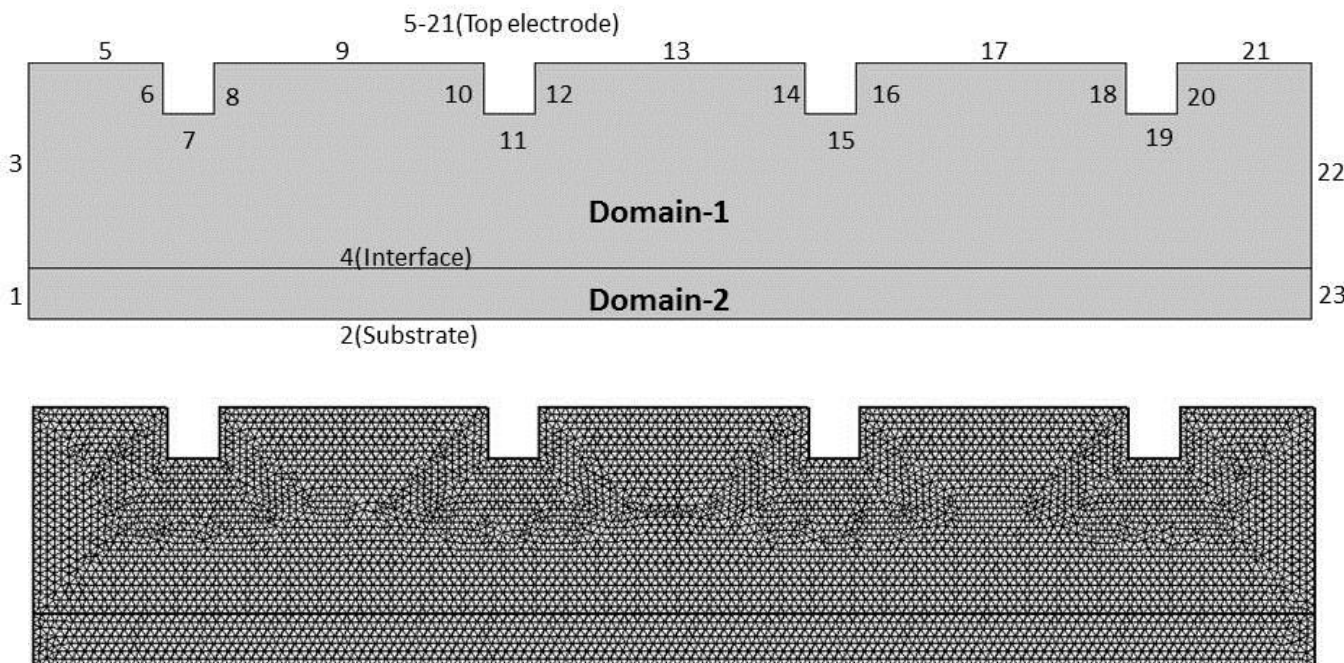




# Patterned electrode



# Computational model



## Domain

- 1 – Air
- 2 – Polymer liquid

## Boundary

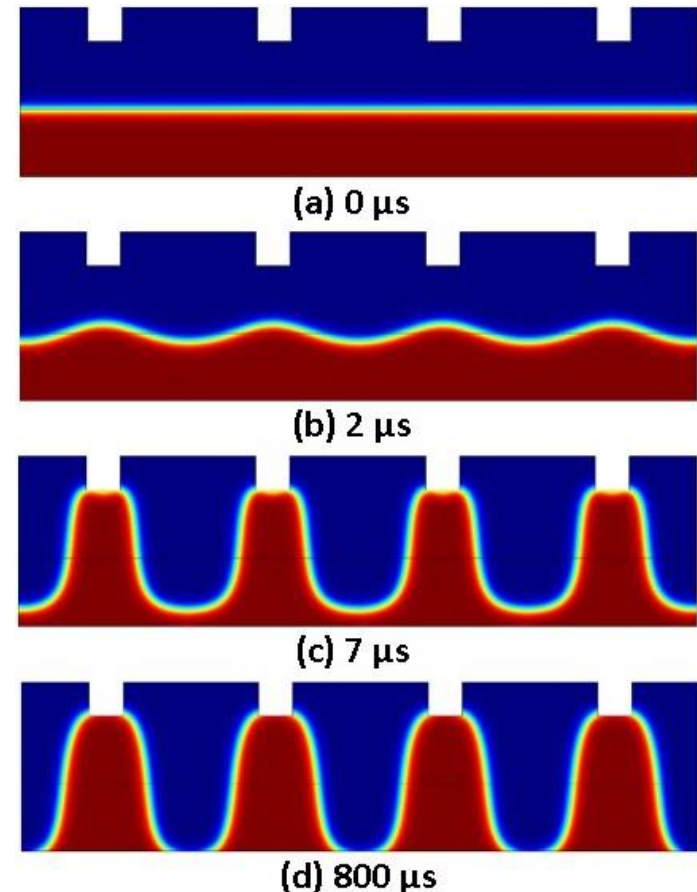
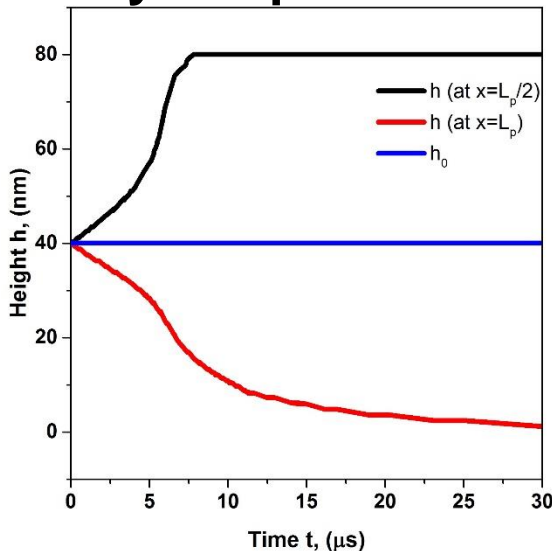
- 5-21 – Top Electrode  
(Wall and Potential U)
- 2 – Ground  
(Wall and Potential 0)
- 4 – Interface
- 1,3 & 22,23 – Periodic

Physics controlled meshing has been done over the system domain

A two dimensional computational model has been developed using  
COMSOL Multiphysics 5.0

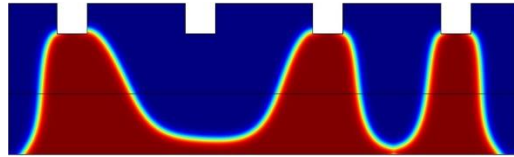
# Pillar formation, Exact replication

- A polymer fluid is coated on ground electrode, bounded by air.
- Heterogeneous electric field destabilizes the interface.
- Surface tension opposes while electrical pressure difference drives the flow.
- Liquid flows from falling crests towards rising peaks.
- Polymer pillars attain pseudo steady state.

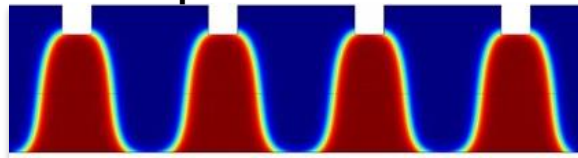


70 V electrical potential is applied through an electrode assembly having 20 nm  $\times$  20 nm square protrusions with periodicity of 100 nm and 100 nm electrode spacing

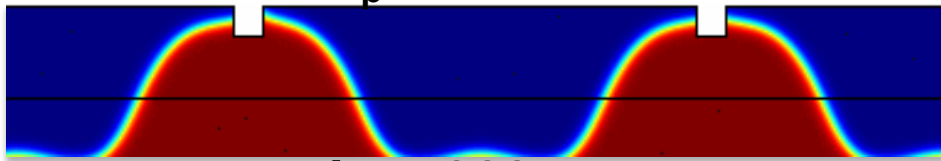
# Effect of period limit



$L_p = 85 \text{ nm}$



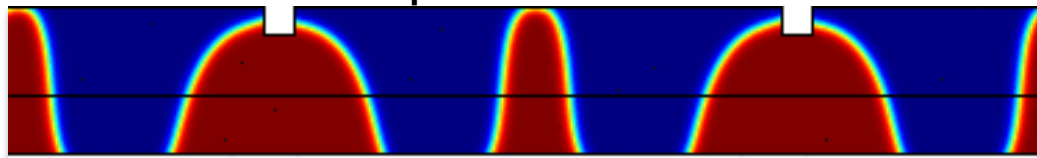
$L_p = 100 \text{ nm}$



$L_p = 300 \text{ nm}$



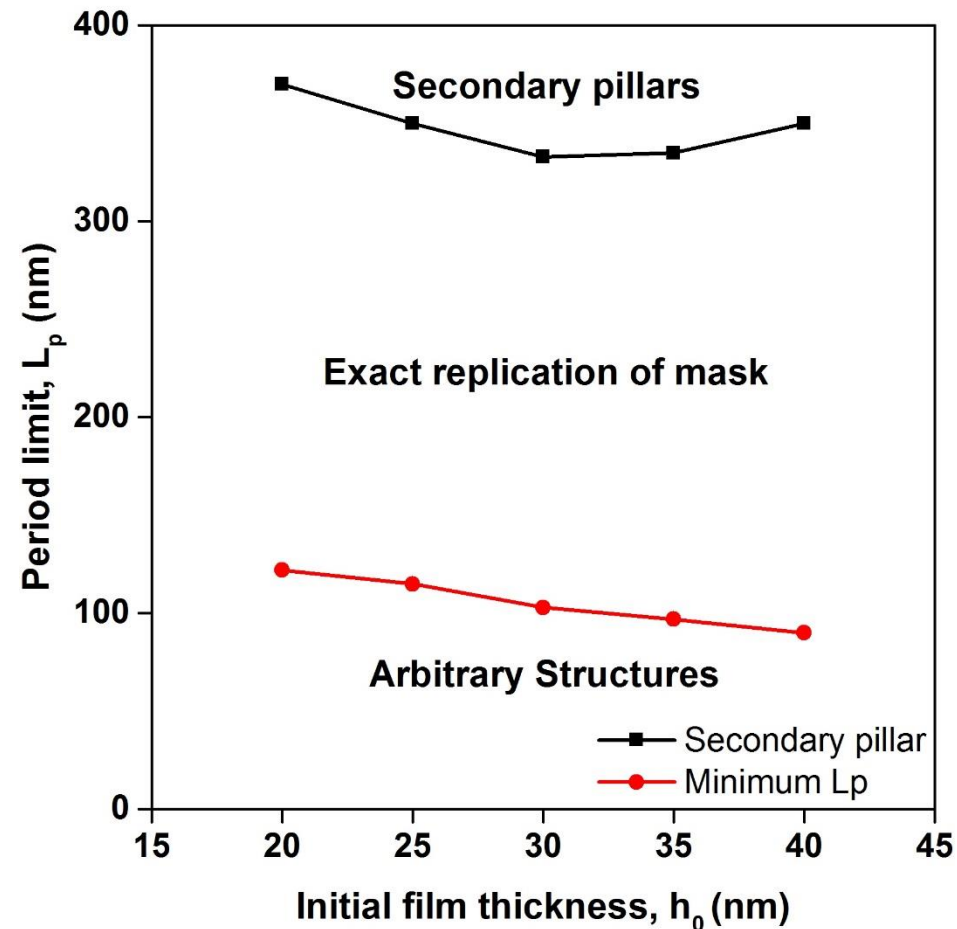
$L_p = 340 \text{ nm}$



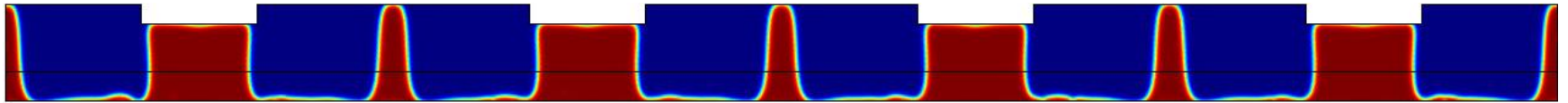
$L_p = 350 \text{ nm}$

# Limitations of patterned electrode

- Verma et al.<sup>1</sup> suggested later quantified by Li et al.<sup>4</sup>, a minimum Period limit required for exact replication of mask
- Upper bound of the same has computationally reported here.
- An unusual trends in the upper limit can be explained when dynamics is observed carefully.



# Effect of electrode width



$w=80$  nm,  $p=20$  nm,  $L_p=400$  nm



$w=150$  nm,  $p=20$  nm,  $L_p=400$  nm



$w=180$  nm,  $p=20$  nm,  $L_p=400$  nm

For all cases

$U=100$  V,  $D=100$  nm,  $H_0=30$  nm

# Final Remarks

- Electric field induced patterning supersedes conventional patterning techniques due to its fast dynamics and low cost.
- A competition between surface tension and electrical forces characterizes a specific wavelength to the system.
- For flat plate, periodicity of structures is equivalent to critical wavelength.
- Linear stability analysis predicts characteristic wavelength ( $\lambda_c$ ) for flat plate as

$$\lambda_c = 2\pi \sqrt{\frac{2\sigma U}{\epsilon_0 \epsilon_p (\epsilon_p - 1)}} E_p^{-3/2}$$

# Final Remarks

- Corner of top electrode helps in rise of instability because of different local electric field.
- Patterned electrode can reduce characteristic lambda of the system resulting in more densely packed pillars.<sup>5</sup>
- Range of nano/micro structures can be obtained by varying period limit.
- Varying electrode width can control morphologies effectively and novel patterns can be developed.



# References

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